

5.3. X-RAY DIFFRACTION METHODS: SINGLE CRYSTAL

cone and normal to the plane of interest, and α is the semivertical angle. Since α depends on the Bragg angle, it is possible to combine (5.3.2.6) with the Bragg law [equations (5.3.1.1) or (5.3.1.2)], and so with the lattice parameters. In particular, the dependence can be presented as:

$$\frac{r}{z'} = \frac{1}{\sin \theta} = \frac{2d}{n\lambda}, \tag{5.3.2.6a}$$

where $r = (x^2 + y^2 + z^2)^{1/2}$.

In another convenient coordinate system (x, y, z) common for all the cones, say with z along the direction of the incident beam, (5.3.2.6a) will take the form:

$$\frac{r}{c_x x + c_y y + c_z z} = \frac{2d}{n\lambda}, \tag{5.3.2.6b}$$

where c_x, c_y, c_z are direction cosines of the angles between the z' axis and the axes x, y and z , respectively. Since the origin of the coordinate system has not been changed,

$$r = (x^2 + y^2 + z^2)^{1/2}. \tag{5.3.2.6c}$$

The Kossel lines (Fig. 5.3.2.3) are formed at the intersections of the cones with a flat film placed parallel to the specimen surface (Fig. 5.3.2.2). When the film plane is normal to the z axis, and the focus-to-film distance is equal to Z , putting $z = Z$ in

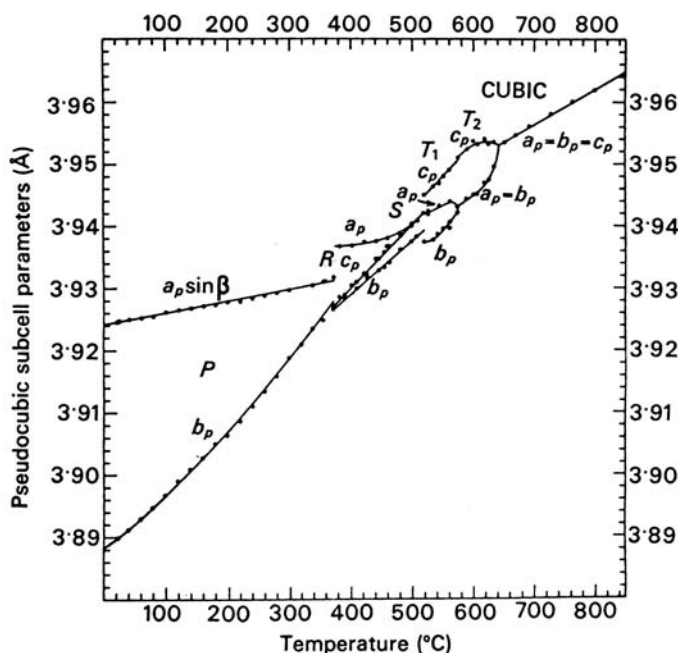
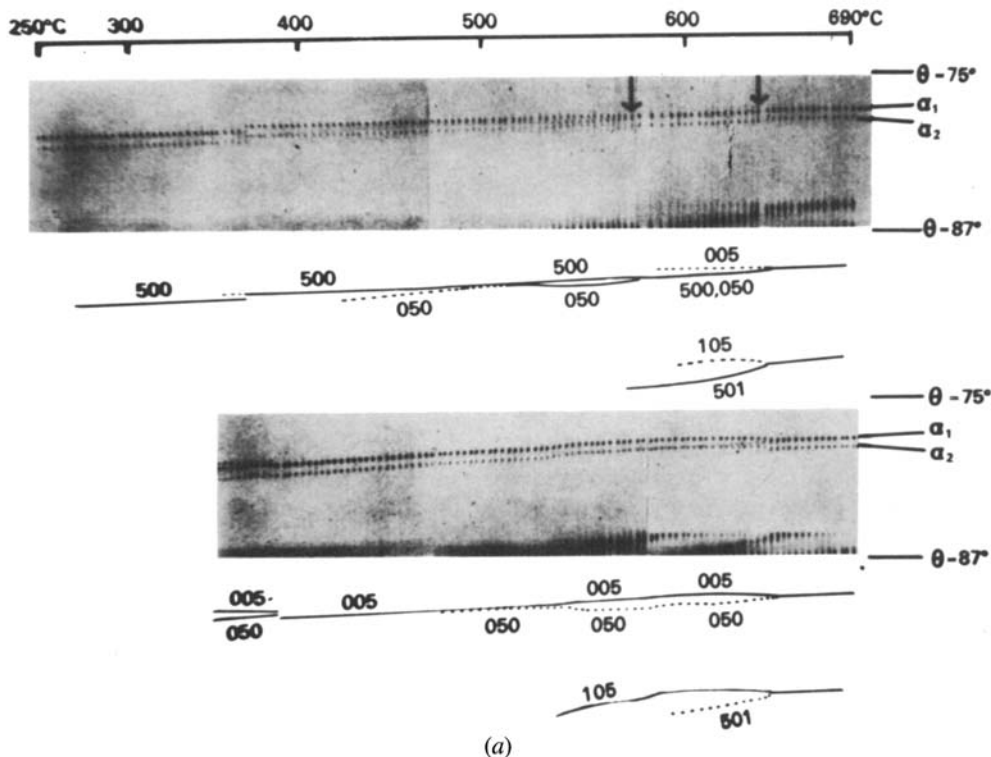


Fig. 5.3.2.1. (a) Photographic recording of lattice-parameter changes. (b) Corresponding diagram of the variation of lattice parameters in pseudocubic NaNbO_3 (Glazer & Megaw, 1973).